

# Supplementary Material for Theoretical Perspective of Performance-limiting Parameters in Cu(In<sub>1-x</sub>Ga<sub>x</sub>)Se<sub>2</sub>-based Photocathodes

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**Table S1.** Material parameters used in electrical simulations of CdS/Cu(In<sub>1-x</sub>Ga<sub>x</sub>)Se<sub>2</sub>-based photocathodes.

Parameters	CdS	Cu(In <sub>1-x</sub> Ga <sub>x</sub> )Se <sub>2</sub>
Thickness	70 nm {ref. 1}	1800 nm {ref. 1}
Effective density of states for conduction and valence band	10 <sup>19</sup> cm <sup>-3</sup> {ref. 2}	10 <sup>19</sup> cm <sup>-3</sup> {ref. 2}
Mole fraction x	-	0-1
Dielectric constant	10 {ref. 1,2}	13.6 {ref. 1}
Doping density	10 <sup>16</sup> cm <sup>-3</sup> (Donor) {ref. 1}	10 <sup>16</sup> cm <sup>-3</sup> (Acceptor) {ref. 1}
Electron affinity	3.8 eV	3.5 (x=0) to 4.2 (x=1) eV <sup>1</sup>
Energy band gap	2.4 eV {ref. 1}	0.98 (x=0) to 1.5 (x=1) <sup>1</sup>
Electron mobility	100 cm <sup>2</sup> /(Vs) {ref. 2}	100 cm <sup>2</sup> /(Vs) {ref. 2}
Hole mobility	25 cm <sup>2</sup> /(Vs) {ref. 2}	25 cm <sup>2</sup> /(Vs) {ref. 2}
Bulk defect density/carrier lifetime	-	10 <sup>13</sup> ,10 <sup>14</sup> cm <sup>-3</sup> /1,0.1 μs

## Parameterization of Optical Constants:

The Forouhi–Bloomer (FB) dispersion relation is generally used to obtain optical constants like the refractive index  $n(E)$  and extinction coefficient  $k(E)$  of crystalline semiconductors<sup>3,4</sup> and is given as

$$k(E) = \left[ \sum_{i=1}^m \frac{A_i}{E^2 - B_i E + C_i} \right] (E - E_g)^2, \quad (1)$$

$$n(E) = n_\infty + \sum_{i=1}^m \frac{B'_i E + C'_i}{E^2 - B_i E + C_i}. \quad (2)$$

Here,  $E_g$  is the onset energy of optical absorption,  $n_\infty$  is the refractive index in the high frequency range, and the independent parameters  $A_i$ ,  $B_i$  and  $C_i$  characterize distinct interband transitions. Every summation term in eq. 1 and 2 is the contribution from either a peak or shoulder in the spectra of extinction coefficient  $k$  and refractive index  $n$ . The upper limit  $m$  is the number of different curvatures observed in optical constant  $k$ . The dependent parameters  $B'_i$  and  $C'_i$  in eq. 2 are calculated using following expressions:

$$B'_i = \frac{A_i}{Q_i} \left[ -\frac{B_i^2}{2} + E_g B_i - E_g^2 + C_i \right],$$

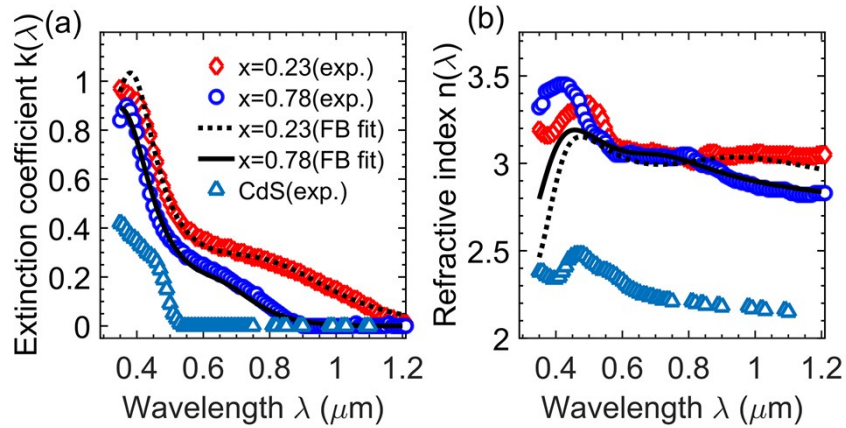
$$C'_i = \frac{A_i}{Q_i} \left[ \frac{B_i(E_g^2 + C_i)}{2} - 2E_g C_i \right],$$

$$Q_i = \frac{1}{2} \sqrt{4C_i - B_i^2}.$$

Each independent parameter, i.e.,  $E_g$ ,  $n_\infty$ ,  $A_i$ ,  $B_i$  and  $C_i$  is approximated by a second-order polynomial of mole fraction  $x$ ; i.e.,  $q_2x^2 + q_1x + q_0$ , where,  $q_0$ ,  $q_1$ , and  $q_2$  are fitting coefficients. Numerical values of fitting coefficients for respective independent parameters are provided in Table S2.

**Table S2:** Numerical values of coefficients of the second-order polynomial ( $q_2x^2 + q_1x + q_0$ ) used to obtain different parameters for parameterization of optical constants such as refractive index  $n(E)$  and extinction coefficient  $k(E)$  using the Forouhi–Bloomer dispersion relation.<sup>4</sup>

Parameter	$q_2$	$q_1$	$q_0$
$A_1$	0.032	-0.128	0.117
$B_1(\text{eV})$	0.82	0.68	2.39
$C_1(\text{eV}^2)$	1.778	0.343	1.738
$A_2$	0.091	0.063	0.066
$B_2(\text{eV})$	-0.54	0.69	5.90
$C_2(\text{eV}^2)$	-1.33	2.60	9.16
$E_g(\text{eV})$	0.26	0.46	0.53
$n_\infty$	0.054	-0.046	2.450



**Figure S1. Parametrization of optical constants using the Forouhi-Bloomer (FB) dispersion relation for CdS/CIGS photocathodes with different mole fraction  $x$ .** Variation of optical constants such as (a) extinction coefficient  $k(\lambda)$  and (b) refractive index  $n(\lambda)$  with wavelength  $\lambda$  for the CIGS layer ( $x=0.23$  and  $0.78$ ) and CdS front window layer. Symbols indicate the extracted experimental data from the literature,<sup>4</sup> while the black solid (for  $x=0.23$ ) and dotted (for  $x=0.78$ ) lines correspond to the FB fit.

The FB fit enables us to calculate optical constants for different  $x$ . For instance, in Fig. S1a, the calculated extinction coefficient  $k$  matches closely with the experimental data over the wavelength range for different  $x$  ( $=0.23$  and  $0.78$ ). Furthermore, Fig. S1b shows that the estimated refractive index  $n$  is in close agreement with actual data at long wavelength, but it deviates at short wavelength ( $<400$  nm). To analyze the effect of the mismatch of  $n$ , we performed optical simulations by incorporating optical constants  $n$  and  $k$  obtained from experiments and the FB fit for  $x=0.23$ .

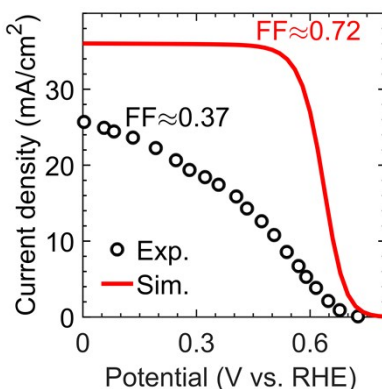


Figure S2. Current potential characteristics (symbols-baseline experimental data; line- simulation) of CdS/CIGS based photocathode with mole fraction  $x=0.5$ . For simulation data, the interface defect density  $N_I = 2.5 \times 10^8 \text{ cm}^{-2}$  and bulk defect density  $N_B = 10^{14} \text{ cm}^{-3}$ .

**Table S3.** Parameters extracted from the comparison of simulation and experimental data of current potential characteristics of CdS/Cu(In<sub>1-x</sub>Ga<sub>x</sub>)Se<sub>2</sub> photocathodes with different mole fraction  $x$ .

Mole fraction $x$	Resistance $R_s$ ( $\Omega \text{ cm}^2$ )	Shunt Resistance $R_{sh}$ ( $\Omega \text{ cm}^2$ )	Interface defect density $N_I$	Bulk life time in CIGS $\tau$ ( $\mu\text{s}$ )	Attenuation constant $A_c$ (%)
0	8.5	25	-	1	73.43
0.5	12	55	$3 \times 10^8 \text{ cm}^{-2}$	1	86.27
0.7	15	168	$12 \times 10^8 \text{ cm}^{-2}$	0.1	61.06
1	25	500	$4 \times 10^8 \text{ cm}^{-2}$	0.1	25

## References:

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